

L Number	Hits	Search Text	DB	Time stamp
1	7417	mem\$3 with asic	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB USPAT;	2004/03/11 10:09
2	7882	memor\$3 with asic	US-PGPUB; EPO; JPO; DERWENT; IBM TDB USPAT;	2004/03/11 10:10
3	1918	memor\$3 with asic with program\$5	US-PGPUB; EPO; JPO; DERWENT; IBM TDB USPAT;	2004/03/11 10:10
4	5	(memor\$3 with asic with program\$5) and ((defect\$3 or bad) with pixel\$1)	US-PGPUB; EPO; JPO; DERWENT; IBM TDB USPAT;	2004/03/11 10:24
5	545	((asic or program\$5) with memor\$3) and ((defect\$3 or bad) with pixel\$1)	US-PGPUB; EPO; JPO; DERWENT; IBM TDB USPAT;	2004/03/11 10:25
6	354	((asic or program\$5) with memor\$3) and ((defect\$3 or bad) with pixel\$1) and @ad<=20001231	US-PGPUB; EPO; JPO; DERWENT; IBM TDB USPAT;	2004/03/11 10:33
7	554	defect\$3 with pixel with memor\$3	US-PGPUB; EPO; JPO; DERWENT; IBM TDB USPAT;	2004/03/11 10:33
8	595	(defect\$3 or bad) with pixel with memor\$3	US-PGPUB; EPO; JPO; DERWENT; IBM TDB USPAT;	2004/03/11 10:34
9	595	(defect\$3 or bad) with pixel with memor\$3	US-PGPUB; EPO; JPO; DERWENT; IBM TDB USPAT;	2004/03/11 10:35
10	443	(defect\$3 or bad) with pixel with memor\$3 and @ad<=20001231	US-PGPUB; EPO; JPO; DERWENT; IBM TDB USPAT;	2004/03/11 10:35
11	443	(defect\$3 or bad) with pixel\$1 with memor\$3 and @ad<=20001231	US-PGPUB; EPO; JPO; DERWENT; IBM TDB USPAT;	2004/03/11 10:37
12	6073	memor\$3 with (contain\$2 or embed\$3) with chip	US-PGPUB; EPO; JPO; DERWENT; IBM TDB USPAT;	2004/03/11 10:37
13	4171	memor\$3 with (contain\$2 or embed\$3) with chip and @ad<=20001231	US-PGPUB; EPO; JPO; DERWENT; IBM TDB USPAT;	2004/03/11 10:38
14	13	memor\$3 with (contain\$2 or embed\$3) with chip and @ad<=20001231 and ((bad or defect\$3) with pixel)	US-PGPUB; EPO; JPO; DERWENT; IBM TDB USPAT;	2004/03/11 13:35

15	237	(break\$2down with gate with logic)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2004/03/11 13:37
16	1	(break\$2down with gate with logic) and (amplif\$4 with leakage)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2004/03/11 13:40
17	40	acces\$4 with leak\$3 with amplif\$7	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2004/03/11 13:41
18	22	(acces\$4 with leak\$3 with amplif\$7) and @ad<=20001231	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2004/03/11 14:02
20	3	(break\$7 with logic with one) and (amplifi\$7 with leak\$3)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2004/03/11 14:03
19	617	break\$7 with logic with one	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2004/03/11 14:05
21	519	break\$7 with logic with one and @ad<=20001231	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2004/03/11 14:07
22	74	break\$2down with logic with one and @ad<=20001231	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2004/03/11 14:09
23	278	float\$3 with gate with logic with one and @ad<=20001231	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2004/03/11 14:15
24	947	fuse with memor\$3 with (transistor or cmos or fet)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2004/03/11 14:16
25	872	fuse with memor\$3 with (transistor)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2004/03/11 14:16
26	3	fuse adj memor\$3 adj (transistor) and @ad<=20001231	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2004/03/11 14:18
27	5145	break\$7 with gate with ((logic with high) or high)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2004/03/11 14:20
28	128	break\$7 with gate with ((logic with high))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2004/03/11 14:20

43	114	348/246.cccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/03/11 15:00
44	79	348/247.cccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/03/11 15:00
45	473	348/241.cccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/03/11 15:00
46	147	348/341.cccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/03/11 15:01
47	0	348/341.cccls. with (defect\$3 or bad) with pixel	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/03/11 15:01
48	2	348/341.cccls. and (defect\$3 or bad) with pixel	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/03/11 15:13
49	13	(HIOK with nam with tay).in.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/03/11 15:14